

register by contacting Evelyn Bohor of the Rocky Mountain Regional Office and TTY/TDD (303) 866-1049 by noon on August 2, 2010.

Members of the public are entitled to submit written comments. The comments must be received in the regional office by September 5, 2010. The address is: U.S. Commission on Civil Rights, Rocky Mountain Regional Office, 1961 Stout Street, Suite 240, Denver, CO 80294. Comments may be e-mailed to ebohor@usccr.gov. Records generated by this meeting may be inspected and reproduced at the Rocky Mountain Regional Office, as they become available, both before and after the meeting. Persons interested in the work of this advisory committee are advised to go to the Commission's Web site, <http://www.usccr.gov>, or to contact the Rocky Mountain Regional Office at the above e-mail or street address.

The meeting will be conducted pursuant to the provisions of the rules and regulations of the Commission and FACA.

Dated in Washington, DC, July 14, 2010.

Peter Minarik,

*Acting Chief, Regional Programs
Coordination Unit.*

[FR Doc. 2010-17532 Filed 7-16-10; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

Saint Louis University, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Avenue, NW., Washington, DC.

Docket Number: 10-019.

Applicant: Saint Louis University, St. Louis, MO 63103.

Instrument: Electron Microscope.

Manufacturer: FEI Co., Czech Republic.

Intended Use: See notice at 75 FR 34096, June 16, 2010.

Docket Number: 10-021.

Applicant: South Dakota School of Mines and Technology, St. Rapid City, SD 57701.

Instrument: Electron Microscope.

Manufacturer: JEOL, Japan.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Docket Number: 10-024.

Applicant: National Institutes of Health, Bethesda, MD 20892-0851.

Instrument: Electron Microscope.

Manufacturer: FEI Co., the Netherlands.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Docket Number: 10-026.

Applicant: National Institutes of Health, Bethesda, MD 20892-0851.

Instrument: Electron Microscope.

Manufacturer: FEI Co., the Netherlands.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Comments: None received.

Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered.

Reasons: Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Dated: July 13, 2010.

Christopher Cassel,

*Director, Subsidies Enforcement Office,
Import Administration.*

[FR Doc. 2010-17537 Filed 7-16-10; 8:45 am]

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DEPARTMENT OF COMMERCE

International Trade Administration

University of Minnesota, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Ave, NW., Washington, DC.

Comments: None received.

Decision: Approved. We know of no instruments of equivalent scientific value to the foreign instruments described below, for such purposes as

this is intended to be used, that were being manufactured in the United States at the time of its order.

Docket Number: 10-025.

Applicant: University of Minnesota, Department of Chemical Engineering and Materials Science, Minneapolis, MN 55455.

Instrument: High Pressure Oxygen Sputtering System.

Manufacturer: Forschungszentrum Juelich GmbH, Germany.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Reasons: A pertinent characteristic of this instrument is that the special design of the sputter sources and vacuum chamber/pumping system allows it to operate properly at pressures in excess of 1 Torr. It also is designed to work in pure oxygen and is capable of substrate heating to over 900 C in a high pressure such an environment. We know of no instrument suited to these purposes, which was being manufactured in the United States at the time of order of this instrument.

Docket Number: 10-027.

Applicant: Argonne National Laboratory, Lemont, IL 60439.

Instrument: MultiView 400 SPM/ NSOM/Confocal Multi Probe System Probe and Sample Scanning Scan Head Assembly.

Manufacturer: Nanonics Imaging Ltd., Israel.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Reasons: A unique characteristic of this system is that it has dual scanning probe heads that are independently controlled, which enable illumination and detection with sub-wavelength spatial resolution. We know of no instrument suited to these purposes, which was being manufactured in the United States at the time of order of this instrument.

Docket Number: 10-028.

Applicant: Boston College, Chestnut Hill, MA 02467.

Instrument: Infrared Mirror Furnace 4 Mirror Furnace.

Manufacturer: Crystal Systems Corp., Japan.

Intended Use: See notice at 75 FR 34095, June 16, 2010.

Reasons: A unique characteristic of this furnace is that it can synthesize extremely high quality crystals without crucible contact during growth, which prevents contamination. The instrument also allows for visual monitoring of the crystals during its growth and nucleation and can achieve heating gradients greater than 1500 Celsius per centimeter. We know of no instrument suited to these purposes, which was being manufactured in the United States at the time of order of this instrument.